FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (USE several Setted BY APPLICANT(S)				ATTY DOCKET NO. 03500.109226.	APPLICATION NO. 10/599,427		
				APPLICANT SEIICHI TAMURA ET AL.			
	,	,		FILING DATE September 28, 2006	GROUP 2811		
				U.S. PATENT DOCUMENTS	,		
*EXAMINER INITIAL	L	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/TC/		6,445,014 B1	09/03/02	Rhodes et al.	257	185	
		5,201,681	04/13/93	Okunuki et al.	445	24	
		5,361,015	11/01/94	Okunuki et al.	313	309	
		5,700,719	12/23/97	Yuzurihara et al.	437	193	
		5,731,131	03/24/98	Momma et al.	430	311	
		5,561,317	10/01/96	Momma et al.	257	620	
		5,466,961	11/14/95	Kikuchi et al.	257	379	
		5,598,037	01/28/97	Kikuchi et al.	257	773	
		6,373,099 B1	04/16/02	Kikuchi et al.	257	331	
		5,918,115	06/29/99	Kikuchi et al.	438	138	
		5,428,237	06/27/95	Yuzurihara et al.	257	349	
		5,612,230	03/18/97	Yuzurihara et al.	437	21	
		5,903,043	05/11/99	Ichikawa et al.	257	532	
\vee		6,049,235	04/11/00	lchikawa et al.	327	51	
			FO	REIGN PATENT DOCUMENTS	,		
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
/TC/	JP	2001-332714	11/30/01	Japan			Abstract
/TC/	JP	2000-232214	08/22/00	Japan			Abstract
-	Measure	ОТН	ER DOCUMENT(S	(Including Author, Title, Date, Pertinent Pages, Etc	.)		

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				APPLICANT SEIICHI TAMURA ET AL.					
				FILING DATE September 28, 2006		GROUP 2811			
				U.S. PATENT DOCUMENTS					
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
/TC/		5,693,959	12/02/97	Inoue et al.	357	66			
/TC/		2005/0127415 A1	06/16/05	Yuzurihara et al.	257	292			
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FOREIGN PATENT DOCUMENTS									
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT		
		OTHE	R DOCUMENT(S	(Including Author, Title, Date, Pertinent Page	s, Etc.)	-			
EXAMINER	/T	92 Chin/ (03/31/2008) DATE CONSIDERED 03/31/2008							

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